# AT25QF128A



## 128 Mbit Serial NOR Flash Memory with Dual and Quad I/O Support

## PRELIMINARY DATASHEET

## Features

- Single voltage operation with range of 2.7V to 3.6V
- Default Operating Mode is SPI Quad I/O
- Serial Peripheral Interface (SPI) compatible support
- Supports SPI modes 0 and 3
  - Supports Dual Output and Quad Output read
  - Supports Dual I/O and Quad I/O read
- Maximum Operating Frequency
  - 133 MHz maximum operating frequency at 85 °C
  - 120 MHz maximum operating frequency at 105 °C
- Read Operations
  - 70 MHz SPI normal read
  - 120 MHz SPI fast read
  - 133 MHz Quad Output fast read at 85 °C
  - Dual I/O data transfer rate up to 240 Mbps
  - Quad I/O data transfer rate up to 480 Mbps
  - Quad Output data transfer rate up to 532 Mbps
  - Continuous read with 8/16/32/64-byte wrap
- Flexible programming
  - Byte/Page program (1 to 256 Bytes)
  - Program suspend and resume
- Fast program and erase times
  - 0.6 ms typical page (256 byte) program time
  - 70 ms typical 4-Kbyte block erase time
  - 150 ms typical 32-Kbyte block erase time
  - 250 ms typical 64-Kbyte block erase time
  - Full chip erase: 30s typical
- Hardware and software Write Protection
  - Hardware-controlled locking of protected sector via WP pin
  - Three 256-byte OTP-capable security registers
  - Write protect all or part of memory via software with top/bottom block selection
- Serial Flash Discoverable Parameter (SFDP) register
- Low power dissipation
  - 13 µA standby current at 85 °C
  - 20 µA standby current at 105 °C
  - 2 µÅ deep power down current at 85 °C
  - 5 µA deep power down current at 105 °C
- Endurance:
  - 100K program/erase cycles at 85 °C
  - 10K program/erase cycles at 105 °C
- Data Retention:
  - 20 years at 85 °C
  - 10 years at 105 °C
- Temperature Range:
  - Industrial: -40 °C to 85 °C
  - Extended Temperature Range: -40 °C to 105 °C
- Industry standard green (Pb/Halide-free/RoHS compliant) package options
  - 8-lead 0.208" Wide SOIC (8S4)
  - 8-pad (5 x 6 x 0.6 mm) UDFN (8MA1)

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## 1. Product Overview

The Adesto® AT25QF128A is a 128-Mbit Serial Peripheral Interface (SPI) Flash memory device designed for use in a wide variety of high-volume consumer based applications in which program code is shadowed from Flash memory into embedded or external RAM for execution. The flexible erase architecture of the AT25QF128A is ideal for data storage as well, eliminating the need for additional data storage devices.

The SPI clock supports a maximum frequency of 133 MHz, enabling data transfers up to 532 Mbits/s for Quad Output operations.

The AT25QF128A array is organized into 65,536 programmable pages of 256-bytes each. Up to 256 bytes can be programmed at a time using the Page Program instructions. Pages can be erased in 4 KB, 32 KB, or 64 KB blocks, or the entire chip.

The devices operate on a single 2.7V to 3.6V power supply with current consumption as low as 2  $\mu$ A for Deep Power Down at 85 °C. All devices offered in space-saving packages. The device supports JEDEC standard manufacturer and device identification with three 256-byte secure OTP registers.

## 2. Package Pinouts

Figure 2-1 show the package pinouts for the following devices.



Figure 2-1. Adesto AT25QF128A Flash Memory Package Types



## 3. Pin Descriptions

During all operations, VCC must be held stable and within the specified valid range: VCC (min) to VCC (max). All of the input and output signals must be held high or low (according to voltages of VIH, VOH, VIL or VOL, see Section 9.6, DC Electrical Characteristics). These pins are described below.

## 3.1 Pin Summary

Pin Name	I/O	Description
CS	I	Chip select.
SO (IO <sub>1</sub> )	I/O	Serial Output for single bit data Instructions. $IO_1$ for dual or quad Instructions.
	I/O	Write Protect in single bit or dual data Instructions. $IO_2$ in quad mode. The signal has an internal pull-up resistor and may be left unconnected in the host system if not used for quad Instructions.
GND		Ground.
SI (IO <sub>0</sub> )	I/O	Serial input for single bit data Instructions. $IO_0$ for dual or quad Instructions.
SCLK	I	Serial clock.
HOLD (IO <sub>3</sub> )	I/O	Hold (pause) serial transfer in single bit or dual data Instructions. $IO_3$ in Quad-I/O mode. The signal has an internal pull-up resistor and may be left unconnected in the host system if not used for Quad Instructions.
VCC		Core and I/O power supply.

### Table 3-1. AT25QF128A Pin Names

## 3.2 Chip Select (CS)

The chip select signal indicates when a instruction for the device is in process and the other signals are relevant for the memory device. When the  $\overline{CS}$  signal is at the logic high state, the device is not selected and all input signals are ignored and all output signals are high impedance. Unless an internal *Program, Erase* or *Write Status Registers* embedded operation is in progress, the device remains in the Standby Power mode. Driving the  $\overline{CS}$  input to logic low state enables the device, placing it in the *Active Power* mode. After Power Up, a falling edge on  $\overline{CS}$  is required prior to the start of any instruction.

## 3.3 Serial Clock (SCLK)

This input signal provides the synchronization reference for the SPI interface. Instructions, addresses, or data input are latched on the rising edge of the SCLK signal. Data output changes after the falling edge of SCLK.

## 3.4 Serial Input (SI or I/O<sub>0</sub>)

This input signal is used to transfer data serially into the device. It receives instructions, addresses, and data to be programmed. Values are latched on the rising edge of serial SCK clock signal.

SI becomes  $I/O_0$  an input and output during Dual and Quad Instructions for receiving instructions, addresses, and data to be programmed (values latched on rising edge of serial SCK clock signal) as well as shifting out data (on the falling edge of SCK).



## 3.5 Serial Data Output (SO or I/O<sub>1</sub>)

This output signal is used to transfer data serially out of the device. Data is shifted out on the falling edge of the serial SCK clock signal.

The SO pin becomes an I/O pin  $(I/O_1)$  during Dual and Quad Instructions for receiving instructions, addresses, and data to be programmed (values latched on rising edge of serial SCK clock signal) as well as shifting out data (on the falling edge of SCK).

# 3.6 Write Protect (WP or I/O<sub>2</sub>)

When  $\overline{\text{WP}}$  is driven low (VIL), while the Status Register Protect bits (SRP1 and SRP0) of the Status Registers (SR2[0] and SR1[7]) are set to 0 and 1 respectively, it is not possible to write to the Status Registers. This prevents any alteration of the Status Registers. As a consequence, all the data bytes in the memory area that are protected by the Block Protect, TB, SEC, and CMP bits in the status registers, are also hardware protected against data modification while  $\overline{\text{WP}}$  remains low. The  $\overline{\text{WP}}$  function is not available when the Quad mode is enabled (QE bit in Status Register 2 = 1).

The  $\overline{\text{WP}}$  function is replaced by I/O<sub>2</sub> for input and output during Quad mode for receiving addresses, and data to be programmed (values are latched on rising edge of the SCK signal) as well as shifting out data (on the falling edge of SCK).  $\overline{\text{WP}}$  has an internal pull-up resistance; when unconnected;  $\overline{\text{WP}}$  is at VIH and may be left unconnected in the host system if not used for Quad mode.

## 3.7 Hold (HOLD or $I/O_3$ )

The HOLD function is only available when the Quad Enable (QE) bit in Status Register 2 = 0. If QE = 1, The HOLD function is disabled and the pin acts as dedicated data I/O pin. Note that the AT25QF128A device ships with the QE bit set at the factory, causing the device to power up in Quad mode.

The HOLD signal goes low to stop any serial communication with the device, but doesn't stop the operation of write status register, programming, or erasing in progress.

The Hold condition starts on the falling edge of the HOLD signal, provided that it coincides with SCK being in the logic low state. If the falling edge does not coincide with the SCK signal being at the logic low state, the Hold condition starts whenever the SCK signal reaches the logic low state. Taking the HOLD signal to the logic low state does not terminate any Write, Program or Erase operation that is currently in progress.



Figure 3-1. HOLD Pin Function

## 3.8 VCC Power Supply

VCC is the supply voltage. It is the single voltage used for all device functions including read, program, and erase.

## 3.9 GND Ground

GND is the ground reference for the VCC supply voltage.



# 4. Block/Sector Addresses

#### Table 4-1. Block/Sector Addresses of AT25QF128A

Memory Density	Block (64k byte)	Block (32k byte)	Sector No.	Sector Size (KB)	Address Range
			Sector 0	4	000000h - 000FFFh
		Half block 0	:	:	:
	Block 0		Sector 7	4	007000h - 007FFFh
	BIOCK		Sector 8	4	008000h - 008FFFh
		Half block 1	:		:
			Sector 15	4	00F000h - 00FFFFh
			Sector 16	4	010000h - 010FFFh
		Half block 2	:	:	:
	Block 1	_	Sector 23	4	017000h - 017FFFh
	BIOCK		Sector 24	4	018000h - 018FFFh
		Half block 3	:	:	:
			Sector 31	4	01F000h - 01FFFFh
128Mbit	:	:	:	:	:
			Sector 4064	4	FE0000h - FE0FFFh
		Half block 508	:	:	:
	Block 254		Sector 4071	4	FE7000h - FE7FFFh
	DIUCK 234		Sector 4072	4	FE8000h - FE8FFFh
		Half block 509	:	:	:
			Sector 4079	4	FEF000h - FEFFFFh
			Sector 4080	4	FF0000h - FF0FFFh
		Half block 510	:	:	:
	Block 255		Sector 4087	4	FF7000h - FF7FFFh
	DIUCK 200		Sector 4088	4	FF8000h - FF8FFFh
		Half block 511	:	:	:
			Sector 4095	4	FFF000h - FFFFFFh

Notes:

- 1. Block = Uniform Block, and the size is 64K bytes.
- 2. Half block = Half Uniform Block, and the size is 32k bytes.
- 3. Sector = Uniform Sector, and the size is 4K bytes.



## 5. SPI Operation

## 5.1 Standard SPI Instructions

The AT25QF128A features a 4-pin serial peripheral interface on 4 signals bus: Serial Clock (SCLK), Chip Select  $\overline{(CS)}$ , Serial Data Input (SI) and Serial Data Output (SO). SPI bus modes 0 and 3 are supported. Input data is latched on the rising edge of SCLK and data shifts out on the falling edge of SCLK.

## 5.2 Dual SPI Instructions

The AT25QF128A supports Dual SPI operation when using the *Dual Output Fast Read* (3BH), *Dual I/O Fast Read* (BBH) and *Read Manufacture ID/Device ID Dual I/O* (92H) instructions. These instructions allow data to be transferred to or from the device at two times the rate of the standard SPI. When using the Dual SPI instruction the SI and SO pins become bidirectional I/O pins:  $I/O_0$  and  $I/O_1$  respectively.

## 5.3 Quad SPI Instructions

The AT25QF28A device ships with the Quad Enable (QE) bit set in the Status Register. This causes the device to power-up in SPI Quad I/O mode.

The AT25QF128A supports Quad SPI operation when using the *Quad Output Fast Read* (6BH), *Quad I/O Fast Read* (EBH), *Quad I/O Word Fast Read* (E7h), *Read Manufacture ID/Device ID Quad I/O* (94H) and *Quad Page Program* (32H) instructions. These instructions allow data to be transferred to or from the device at four times the rate of the standard SPI. When using the Quad SPI instruction the SI and SO pins become bidirectional I/O pins:  $I/O_0$  and  $I/O_1$ , and /WP and HOLD pins become  $I/O_2$  and  $I/O_3$ . Quad SPI instructions require the non-volatile Quad Enable bit (QE) in Status Register to be set.

# 6. Operating Features

## 6.1 Supply Voltage

## 6.1.1 Operating Supply Voltage

Prior to selecting the memory and issuing instructions to it, a valid and stable VCC voltage within the specified VCC (min) / VCC (max) range must be applied. In order to secure a stable DC supply voltage, it is recommended to decouple the VCC line with capacitors (usually 10 nF to 100 nF in parallel) placed close to the VCC/GND package pins. This voltage must remain stable and valid until the end of the transmission of the instruction and, for a Write instruction, until the completion of the internal write cycle ( $t_W$ ).

## 6.1.2 Power-up Conditions

When the power supply is turned on, VCC rises continuously from GND to VCC. During this time, the Chip Select  $\overline{(CS)}$  line is not allowed to float but should follow the VCC voltage, it is therefore recommended to connect the  $\overline{CS}$  line to VCC via a pull-up resistor.

In addition, the  $\overline{CS}$  input is both edge sensitive and level sensitive. After power-up, the device does not become selected until a falling edge is first detected on  $\overline{CS}$ . This ensures that  $\overline{CS}$  must have been High, prior to going Low to start the first operation.

## 6.1.3 Device Reset

In order to prevent inadvertent Write operations during power-up (continuous rise of VCC), a power on reset (POR) circuit is included. At Power-up, the device does not respond to any instruction until VCC has reached the power



on reset threshold voltage (this threshold is lower than the minimum VCC operating voltage defined by the DC operating ranges).

When VCC has passed the POR threshold, the device is reset.

## 6.1.4 Power-down

At Power-down (continuous decrease in VCC), as soon as VCC drops from the normal operating voltage to below the power on reset threshold voltage, the device stops responding to any instruction sent to it. During Power-down, the device must be deselected (Chip Select  $\overline{(CS)}$  should be allowed to follow the voltage applied on VCC) and in Standby Power mode (that is there should be no internal Write cycle in progress).

## 6.2 Active Power and Standby Power Modes

When Chip Select  $(\overline{CS})$  is low, the device is selected and in the Active Power mode and consuming current (ICC). When Chip Select  $(\overline{CS})$  is high, the device is deselected. If a Write cycle is not currently in progress, the device enters the Standby Power mode, and the current consumption drops to ICC1.

## 6.3 Hold Condition

The Hold (HOLD) signal is used to pause any serial communications with the device without resetting the clocking sequence. During the Hold condition, the Serial Data Output (SO) is high impedance, and Serial Data Input (SI) and Serial Clock (SCLK) are don't care. Note that the HOLD function can only be used with the QE bit of the Status Register = 0.

To enter the Hold condition, the device must be selected, with Chip Select ( $\overline{CS}$ ) low. Normally, the device remains selected for the duration of the Hold condition. Deselecting the device while it is in the Hold condition, has the effect of resetting the state of the device, and this mechanism can be used if it is required to reset any processes that had been in progress.

The Hold condition starts when the Hold ( $\overline{HOLD}$ ) signal is driven Low at the same time as Serial Clock (SCLK) already being Low (as shown in Figure 6-1).

The Hold condition ends when the Hold (HOLD) signal is driven High at the same time as Serial Clock (C) already being Low. Figure 6-1 also shows what happens if the rising and falling edges are not timed to coincide with Serial Clock (SCLK) being Low.



Figure 6-1. Hold Condition Activation



## 6.4 Status Register

The AT25QF128A contains three Status registers. Each byte is written or read using specific instructions. For a read operation, the 05h, 35h, and 15h instructions are used to access the S7 - S0, S15 - S8, and S23 - S16 bytes respectively. For a write operation, the 01h, 31h, and 11h instructions are used as shown in Table 8-1.

The following diagram shows the layout of the Status Register bits.

S23	S22	S21	S20	S19	S18	S17	S16
Reserved	DRV1	DRV0	Reserved	Reserved	Reserved	Reserved	Reserved

S15	S14	S13	S12	S11	S10	S9	S8
SUS1	CMP	LB3	LB2	LB1	SUS2	QE	SRP1

S7	S6	S5	S4	S3	S2	S1	S0
SRP0	BP4	BP3	BP2	BP1	BP0	WEL	WIP

#### Figure 6-2. Status Register Bit Layout

### 6.4.1 Status Register Bit Definitions

#### 6.4.1.1 WIP bit (S0)

The Write in Progress (WIP) bit indicates whether the memory is busy in program/erase/write status register progress. When WIP bit sets to 1, means the device is busy in program/erase/write status register progress, when WIP bit sets 0, means the device is not in program/erase/write status register progress.

### 6.4.1.2 WEL bit (S1)

The Write Enable Latch bit indicates the status of the internal Write Enable Latch. When set to 1 the internal Write Enable Latch is set, when set to 0 the internal Write Enable Latch is reset and no Write Status Register, Program or Erase instruction is accepted.

#### 6.4.1.3 BP4, BP3, BP2, BP1, BP0 Bits (S6 - S2)

The Block Protect (BP4, BP3, BP2, BP1, BP0) bits are non-volatile. They define the size of the area to be software protected against Program and Erase instructions. These bits are written with the Write Status Register instruction.

- When the Block Protect (BP4, BP3, BP2, BP1, BP0) bits are set to 1, the relevant memory becomes protected against Page Program, Sector Erase and Block Erase instructions.
- The Block Protect (BP4, BP3, BP2, BP1, BP0) bits can be written provided that the Hardware Protected mode has not been set.
- The Chip Erase (CE) instruction is executed if the Block Protect (BP2, BP1, BP0) bits are 0 and CMP = 0 or the Block Protect (BP2, BP1, BP0) bits are 1 and CMP = 1.

#### 6.4.1.4 SRP1, SRP0 Bits (S8 - S7)

The Status Register Protect (SRP1 and SRP0) bits are non-volatile Read/Write bits in the status register. The SRP bits control the method of write protection: software protection, hardware protection, power supply lock-down or one time programmable protection.



#### 6.4.1.5 QE Bit (S9)

The Quad Enable (QE) bit is a non-volatile Read/Write bit in the Status Register that allows Quad operation. When the QE bit is set to 0 the  $\overline{WP}$  pin and  $\overline{HOLD}$  pin are enable. When the QE pin is set to 1 (Default), the Quad I/O<sub>2</sub> and I/O<sub>3</sub> pins are enabled. The QE bit is set at the factory and the device powers up in Quad mode.

The QE bit should never be set during standard SPI or Dual SPI operation if the WP or HOLD pins directly to either power or ground. Note that if these pins are connected to power or ground, software must first clear the QE bit.

### 6.4.1.6 SUS1/SUS2 Bits (S15, S10)

The SUS1 and SUS2 bits are read only bits in the status register2 (S15 and S10) that are set to 1 after executing an Erase/Program Suspend (75h) instruction (The Erase Suspend sets SUS1 to 1, and the Program Suspend sets SUS2 to 1). The SUS1 and SUS2 bits are cleared to 0 by Erase/Program Resume (7Ah) instruction as well as a power-down, power-up cycle.

### 6.4.1.7 LB3/LB2/LB1 bit (S13 - S11)

The LB bits are non-volatile One Time Program (OTP) bits in Status Register (S13 - S11) that provide the write protect control and status to the Security Registers. The default state of LBx is 0, the security registers are unlocked. The LBx bits can be set to 1 individually using the Write Register instruction. The LBx bits are One Time Programmable. Once they are set to 1, the Security Registers become read-only permanently.

### 6.4.1.8 CMP Bit (S14)

The CMP bit is a non-volatile Read/Write bit in the Status Register (S14). It is used in conjunction the SEC and BP0 bits to provide more flexibility for the array protection. Please see the Status registers Memory Protection table for details. The default setting is CMP = 0.

### 6.4.1.9 DRV1/DRV0 Bits (S22, S21)

The DRV1 and DRV0 bits are used to determine the output driver strength for the Read instruction.

DRV1, DRV0	Driver Strength
00	100% (default)
01	75%
10	50%
11	25%

#### Table 6-1. DRV1 / DRV0 Bit Encoding

#### 6.4.2 Status Register Protect Table

The Status Register Protect (SRP1 and SRP0) bit are non-volatile Read/Write bits in the Status Register. The SRP bits control the method of write protection: software protection, hardware protection, power supply lock-down or one time programmable protection.



SRP1	SRP0	WP	Status Register	Description
0	0	х	Software Protected	The Status Register can be written to after a Write Enable instruction, WEL = 1 (Factory Default).
0	1	0	Hardware Protected	$\overline{WP}$ = 0, the Status Register locked and cannot be written.
0	1	1	Hardware Unprotected	$\overline{\text{WP}}$ = 1, the Status Register is unlocked and can be written to after a Write Enable instruction, WEL = 1.
1	0	Х	Power Supply Lock-Down <sup>(1)</sup>	Status Register is protected and cannot be written to again until the next Power-Down, Power-Up cycle.
1	1	х	One Time Program <sup>(2)</sup>	Status Register is permanently protected and cannot be written to.

#### Table 6-2. Status Register protect table

Notes:

- 1. When SRP1, SRP0 = (1, 0), a Power-Down, Power-Up cycle will change SRP1, SRP0 to (0, 0) state.
- 2. The One time Program feature is available upon special order. Please contact Adesto for details.

#### 6.4.3 Write Protect Features

- 1. Software Protection: The Block Protect (BP4, BP3, BP2, BP1, BP0) bits define the section of the memory array that can be read but not change.
- 2. Hardware Protection: WP going low to protected the writable bits of Status Register.
- 3. Deep Power-Down: In Deep Power-Down mode, all instructions are ignored except the *Release from Deep Power-Down Mode* instruction.
- 4. Write Enable: The Write Enable instruction is set the Write Enable Latch (WEL) bit. The WEL bit is reset under any of the following conditions:
  - Power -up
  - Write Disable
  - Write Status Register
  - Page Program
  - Sector Erase/Block Erase/Chip Erase
  - Software Reset



## 6.4.4 Status Register Memory Protection

### 6.4.4.1 Protect Table

## Table 6-3. AT25QF128A Status Register Memory Protection (CMP = 0)

	Status F	Register	Content	:		Memory Co	ontent	
BP4	BP3	BP2	BP1	BP0	Blocks	Addresses	Density	Portion
Х	Х	0	0	0	NONE	NONE	NONE	NONE
0	0	0	0	1	252 to 255	FC0000h - FFFFFFh	256 kB	Upper 1/64
0	0	0	1	0	248 to 255	F80000h - FFFFFFh	512 kB	Upper 1/32
0	0	0	1	1	240 to 255	F00000h - FFFFFFh	1 MB	Upper 1/16
0	0	1	0	0	224 to 255	E00000h - FFFFFFh	2 MB	Upper 1/8
0	0	1	0	1	192 to 255	C00000h - FFFFFh	4 MB	Upper 1/4
0	0	1	1	0	128 to 255	800000h - FFFFFFh	8 MB	Upper 1/2
0	1	0	0	1	0 to 3	000000h - 03FFFFh	256 kB	Upper 1/64
0	1	0	1	0	0 to 7	000000h - 07FFFFh	512 kB	Upper 1/32
0	1	0	1	1	0 to 15	000000h - 0FFFFFh	1 MB	Upper 1/16
0	1	1	0	0	0 to 31	000000h - 1FFFFFh	2 MB	Upper 1/8
0	1	1	0	1	0 to 63	000000h - 3FFFFFh	4 MB	Upper 1/4
0	1	1	1	0	0 to 127	000000h - 7FFFFFh	8 MB	Upper 1/2
Х	Х	1	1	1	0 to 255	000000h - FFFFFFh	16 MB	ALL
1	0	0	0	1	255	FFF000h - FFFFFFh	4 kB	Top Block
1	0	0	1	0	255	FFE000h - FFFFFFh	8 kB	Top Block
1	0	0	1	1	255	FFC000h - FFFFFFh	16 kB	Top Block
1	0	1	0	Х	255	FF8000h - FFFFFFh	32 kB	Top Block
1	0	1	1	0	255	FF8000h - FFFFFFh	32 kB	Top Block
1	1	0	0	1	0	000000h - 000FFFh	4 kB	Bottom Block
1	1	0	1	0	0	000000h - 001FFFh	8 kB	Bottom Block
1	1	0	1	1	0	000000h - 003FFFh	16 kB	Bottom Block
1	1	1	0	Х	0	000000h - 007FFFh	32 kB	Bottom Block
1	1	1	1	0	0	000000h - 007FFFh	32 kB	Bottom Block



## Table 6-4. AT25QF128A Status Register Memory Protection (CMP = 1)

	Status F	Register	Content	:		Memory C	ontent	
BP4	BP3	BP2	BP1	BP0	Blocks	Addresses	Density	Portion
Х	х	0	0	0	0 to 255	000000h - FFFFFFh	ALL	ALL
0	0	0	0	1	0 to 251	000000h - FBFFFFh	16128 kB	Lower 63/64
0	0	0	1	0	0 to 247	000000h - F7FFFFh	15872 kB	Lower 31/32
0	0	0	1	1	0 to 239	000000h - EFFFFFh	15 KB	Lower 15/16
0	0	1	0	0	0 to 223	000000h - DFFFFFh	14 MB	Lower 7/8
0	0	1	0	1	0 to 191	000000h - BFFFFFh	12 MB	Lower 3/4
0	0	1	1	0	0 to 127	000000h - 7FFFFFh	8 MB	Lower 1/2
0	1	0	0	1	4 to 255	040000h - FFFFFFh	16,128 kB	Upper 63/64
0	1	0	1	0	8 to 255	080000h - FFFFFFh	15,872 kB	Upper 31/32
0	1	0	1	1	16 to 255	100000h - FFFFFFh	15 kB	Upper 15/16
0	1	1	0	0	32 to 255	200000h - FFFFFFh	14 MB	Upper 7/8
0	1	1	0	1	64 to 255	400000h - FFFFFFh	12 MB	Upper 3/4
0	1	1	1	0	128 to 255	800000h - FFFFFFh	8 MB	Upper 1/2
Х	Х	1	1	1	NONE	NONE	NONE	NONE
1	0	0	0	1	0 to 255	000000h - FFEFFFh	16380 kB	L-4095/4096
1	0	0	1	0	0 to 255	000000h - FFDFFFh	16376 kB	L-2047/2048
1	0	0	1	1	0 to 255	000000h - FFBFFFh	16368 kB	L-1023/1024
1	0	1	0	Х	0 to 255	000000h - FF7FFFh	16352 kB	L-511/512
1	0	1	1	0	0 to 255	000000h - FF7FFFh	16352 kB	L-511/512
1	1	0	0	1	0 to 255	001000h - FFFFFFh	16380 kB	U-4095/4096
1	1	0	1	0	0 to 255	002000h - FFFFFFh	16376 kB	U-2047/2048
1	1	0	1	1	0 to 255	004000h - FFFFFFh	16368 kB	U-1023/1024
1	1	1	0	х	0 to 255	008000h - FFFFFFh	16352 kB	U-511/512
1	1	1	1	0	0 to 255	008000h - FFFFFFh	16352 kB	U-511/512



# 7. Device Identification

Three legacy Instructions are supported to access device identification that can indicate the manufacturer, device type, and capacity (density). The returned data bytes provide the information as shown in the below table.

Operating Code	M7-M0	ID15-ID8	ID7-ID0
9Fh	1Fh	89h	01h
90h/92h/94h	1Fh		17h
ABh			17h

Table 7-1. AT25QF128A ID Definition table

## 8. Instruction Descriptions

All instructions, addresses and data are shifted in and out of the device, beginning with the most significant bit on the first rising edge of SCLK after  $\overline{CS}$  is driven low. Then, the one byte instruction code must be shifted in to the device, most significant bit first on SI, each bit being latched on the rising edges of SCLK.

See Table 8-1, every instruction sequence starts with a one-byte instruction code. Depending on the instruction, this might be followed by address bytes, data bytes, both, or none. The  $\overline{CS}$  pin must be driven high after the last bit of the instruction sequence has been shifted in.

For the *Read*, *Fast Read*, *Read Status Register*, *Release from Deep Power Down*, and *Read Device ID* instructions, the shifted-in instruction sequence is followed by a data out sequence. The  $\overline{CS}$  pin can be driven high after any bit of the data-out sequence is being shifted out.

For the instruction of Page Program, Sector Erase, Block Erase, Chip Erase, Write Status Register, Write Enable, Write Disable or Deep Power-Down instruction,  $\overline{CS}$  must be driven high exactly at a byte boundary, otherwise the instruction is rejected, and is not executed. That is  $\overline{CS}$  must driven high when the number of clock pulses after  $\overline{CS}$  being driven low is an exact multiple of eight. For Page Program, if at any time the input byte is not a full byte, nothing will happen and WEL will not be reset.

Instruction Name	Byte 1	Byte 2	Byte 3	Byte 4	Byte 5	Byte 6	N-Bytes
Write Enable	06h						
Write Disable	04h						
Read Status Register-1	05h	(S7 - S0)					continuous
Read Status Register-2	35h	(S15 - S8)					continuous
Read Status Register-3	15h	(S23 - S16)					continuous
Write Enable for Volatile Status Register	50h						
Write Status Register-1	01h	(S7 - S0)					
Write Status Register-2	31h	(S15 - S8)					
Write Status Register-3	11h	(S23 - S16)					
Read Data	03h	A23 - A16	A15 - A8	A7 - A0	(D7 - D0)	Next byte	continuous
Fast Read	0Bh	A23 - A16	A15 - A8	A7 - A0	dummy	(D7 - D0)	continuous

Table 8-1. Instruction Set



Instruction Name	Byte 1	Byte 2	Byte 3	Byte 4	Byte 5	Byte 6	N-Bytes
Dual Output Fast Read	3Bh	A23 - A16	A15 - A8	A7 - A0	dummy	(D7 - D0) <sup>(1)</sup>	continuous
	100		A 15 - Ao A7 - A0		uunniny	(07 - 00), '	continuous
Dual I/O Fast Read	BBh	A23 - A8 <sup>(2)</sup>	M7 - M0 <sup>(2)</sup>	(D7 - D0) <sup>(1)</sup>	Next byte	Next byte	continuous
Quad Output Fast Read	6Bh	A23 - A16	A15 - A8	A7 - A0	dummy	(D7 - D0) <sup>(3)</sup>	continuous
Quad I/O Fast Read	EBh	A23 - A0 M7 - M0 <sup>(4)</sup>	dummy <sup>(5)</sup>	(D7 - D0) <sup>(3)</sup>	Next byte	Next byte	continuous
Quad I/O Word Fast Read <sup>(7)</sup>	E7h	A23 - A0 M7 - M0 <sup>(4)</sup>	dummy <sup>(6)</sup>	(D7 - D0) <sup>(3)</sup>	Next byte	Next byte	continuous
Page Program	02h	A23 - A16	A15 - A8	A7 - A0	(D7 - D0)	Next byte	continuous
Quad Page Program	32h	A23 - A16	A15 - A8	A7 - A0	(D7 - D0) <sup>(3)</sup>	Next byte	continuous
Fast Page Program	F2h	A23 - A16	A15 - A8	A7 - A0	(D7 - D0)	Next byte	continuous
Sector Erase	20h	A23 - A16	A15 - A8	A7 - A0			
Block Erase(32K)	52h	A23 - A16	A15 - A8	A7 - A0			
Block Erase (64K)	D8h	A23 - A16	A15 - A8	A7 - A0			
Chip Erase	C7/60h						
Enable Reset	66h						
Reset	99h						
Set Burst with Wrap	77h	dummy <sup>(6)</sup> W7 - W0					
Program/Erase Suspend	75h						
Program/Erase Resume	7Ah						
Deep Power-Down	B9h						
Release From Deep Power-Down, And Read Device ID	ABh	dummy	dummy	dummy	(ID7 - ID0)		continuous
Release From Deep Power-Down	ABh						
Manufacturer/ Device ID	90h	dummy	dummy	00H	(MID7 - MID0)	(ID7 - ID0)	continuous
Manufacturer/ Device ID by Dual I/O	92h	A23 - A8	A7 - A0, dummy	(MID7 - MID0), (DID7 -DID0)			continuous
Manufacturer/ Device ID by Quad I/O	94h	A23 - A0, dummy	dummy <sup>(10)</sup> (MID7 - MID0) (DID7 - DID0)				continuous
JEDEC ID	9Fh	MID7 - MID0	ID15 - ID8	ID7-ID0			continuous

## Table 8-1. Instruction Set (continued)



Instruction Name	Byte 1	Byte 2	Byte 3	Byte 4	Byte 5	Byte 6	N-Bytes
Read Serial Flash Discoverable Parameter	5Ah	A23 - A16	A15 - A8	A7-A0	Dummy	D7 - D0	continuous
Erase Security Registers <sup>(8)</sup>	44h	A23 - A16	A15 - A8	A7-A0			
Program Security Registers <sup>(8)</sup>	42h	A23 - A16	A15 - A8	A7-A0	(D7 - D0)	(D7 - D0)	continuous
Read Security Registers <sup>(8)</sup>	48h	A23 - A16	A15 - A8	A7-A0	dummy	(D7 - D0)	continuous

#### Table 8-1. Instruction Set (continued)

Notes:

1. Dual Output data

 $IO_0 = (D6, D4, D2, D0)$ 

 $IO_1 = (D7, D5, D3, D1)$ 

2. Dual Input Address

IO<sub>0</sub> = A22, A20, A18, A16, A14, A12, A10, A8, A6, A4, A2, A0, M6, M4, M2, M0

IO<sub>1</sub> = A23, A21, A19, A17, A15, A13, A11, A9, A7, A5, A3, A1, M7, M5, M3,M1

3. Quad Output Data

IO<sub>0</sub> = (D4, D0,....)

- IO<sub>1</sub> = (D5, D1,....)
- IO<sub>2</sub> = (D6, D2,....)
- IO<sub>3</sub> = (D7, D3,....)
- 4. Quad Input Address
  - IO<sub>0</sub> = A20, A16, A12, A8, A4, A0, M4, M0

IO<sub>1</sub> = A21, A17, A13, A9, A5, A1, M5, M1

IO<sub>2</sub> = A22, A18, A14, A10, A6, A2, M6, M2

- IO<sub>3</sub> = A23, A19, A15, A11, A7, A3, M7, M3
- 5. Fast Read Quad I/O Data
  - $IO_0 = (x, x, x, x, D4, D0,...)$
  - IO<sub>1</sub> = (x, x, x, x, D5, D1,...)
  - IO<sub>2</sub> = (x, x, x, x, D6, D2,...)

$$IO_3 = (x, x, x, x, D7, D3,...)$$

6. Fast Word Read Quad I/O Data

$$IO_0 = (x, x, D4, D0,...)$$

$$IO_2 = (x, x, D6, D2,...)$$

- $IO_3 = (x, x, D7, D3,...)$
- 7. Fast Word Read Quad I/O Data:the lowest address bit must be 0.
- 8. Security Registers Address:

Security Register 1: A23 - A16 = 00h, A15 - A8 = 00010000b, A7 - A0 = Byte Address; Security Register 2: A23 - A16 = 00h, A15 - A8 = 0010000b, A7 - A0 = Byte Address;



Security Register 3: A23 - A16 = 00h, A15 - A8 = 00110000b, A7 - A0 = Byte Address;

9. Dummy bits and Wraps Bits

 $IO_0 = (x, x, x, x, x, x, w4, x)$  $IO_1 = (x, x, x, x, x, x, w5, x)$  $IO_2 = (x, x, x, x, x, x, w6, x)$ 

 $IO_3 = (x, x, x, x, x, x, x, x, x)$ 

10. Address, continuous Read Mode bits, Dummy bits, Manufacture ID and Device ID  $IO_0 = (A20, A16, A12, A8, A4, A0, M4, M0, x, x, x, x, MID4, MID0, DID4, DID0)$   $IO_1 = (A21, A17, A13, A9, A5, A1, M5, M1, x, x, x, x, MID5, MID1, DID5, DID1)$   $IO_2 = (A22, A18, A14, A10, A6, A2, M6, M2, x, x, x, x, MID6, MID2, DID6, DID2)$  $IO_3 = (A23, A19, A15, A11, A7, A3, M7, M3, x, x, x, x, MID7, MID3, DID7, DID3)$ 

Security Register 0 can be used to store the Flash Discoverable Parameters,

The feature is upon special order, please contact Adesto for details.



## 8.1 Configuration and Status Instructions

## 8.1.1 Write Enable (06h)

The Write Enable instruction is for setting the Write Enable Latch (WEL) bit. The WEL bit must be set prior to every *Page Program, Sector Erase, Block Erase, Chip Erase, Write Status Register, and Erase/Program Security Registers* instruction.

The Write Enable instruction sequence:  $\overline{CS}$  goes low sending the Write Enable instruction  $\overline{CS}$  goes high.



Figure 8-1. Write Enable Sequence Diagram

## 8.1.2 Write Disable (04h)

The Write Disable instruction is for resetting the Write Enable Latch bit. The Write Disable instruction sequence:  $\overline{CS}$  goes low -> sending the Write Disable instruction ->  $\overline{CS}$  goes high. The WEL bit is reset by following condition: Power-up and upon completion of the *Write Status Register*, *Page Program*, *Sector Erase*, *Block Erase*, *Chip Erase*, *Erase*, *Program Security Registers*, and *Reset* instructions.





## 8.1.3 Read Status Register (05h or 35h or 15h)

The Read Status Register (RDSR) instruction is for reading the Status Register. The Status Register may be read at any time, even while a Program, Erase or Write Status Register cycle is in progress. When one of these cycles is in progress, it is recommended to check the Write in Progress (WIP) bit before sending a new instruction to the device. It is also possible to read the Status Register continuously. For instruction code 05h, the SO outputs Status Register bits S7 - S0. For instruction code 35h, the SO outputs Status Register bits S15 - S8. For instruction code 15h, the SO outputs Status Register bits S23 - 16.



Figure 8-3 shows a Read Status Register operation for Status Register 1 (05h). The Read Status Register 2 and 3 operations would be the same, but with a different opcode in the first eight clocks.





### 8.1.4 Write Status Register (01h or 31h or 11h)

The Write Status Register instruction allows new values to be written to the Status Register. Before it can be accepted, a Write Enable instruction must previously have been executed. After the Write Enable instruction has been decoded and executed, the device sets the Write Enable Latch (WEL).

The Write Status Register instruction has no effect on S23, S20, S19, S18, S17, S16, S15, S1 and S0 of the Status Register.  $\overline{CS}$  must be driven high after the eighth bit of the data byte has been latched in. If not, the Write Status Register instruction is not executed. As soon as  $\overline{CS}$  is driven high, the self-timed Write Status Register cycle (whose duration is  $t_W$ ) is initiated. While the Write Status Register cycle is in progress, the Status Register may still be read to check the value of the Write in Progress (WIP) bit. This bit is 1 during the self-timed Write Status Register cycle, and is 0 when it is completed. When the cycle is completed, the WEL bit is reset.

The Write Status Register instruction allows the user to change the values of the Block Protect (BP4, BP3, BP2, BP1, BP0) bits, to define the size of the area that is to be treated as read-only. The Write Status Register instruction also allows the user to set or reset the Status Register Protect (SRP1 and SRP0) bits in accordance with the Write Protect (WP) signal. The Status Register Protect (SRP1 and SRP0) bits and Write Protect (WP) signal allow the device to be put in the Hardware Protected Mode. The Write Status Register instruction is not executed once the Hardware Protected Mode is entered.

Figure 8-3 shows a Write Status Register operation for Status Register 1 (01h). The Write Status Register 2 and 3 operations would be the same, but with a different opcode in the first eight clocks.



Figure 8-4. Write Status Register Sequence Diagram



### 8.1.5 Write Enable for Volatile Status Register (50h)

The non-volatile Status Register bits can also be written to as volatile bits. This gives more flexibility to change the system configuration and memory protection schemes quickly without waiting for the typical non-volatile bit write cycles or affecting the endurance of the Status Register non-volatile bits. The Write Enable for Volatile Status Register instruction does not set the Write Enable Latch bit, it is only valid for the Write Status Registers instruction to change the volatile Status Register bit values.



Figure 8-5. Write Enable for Volatile Status Register

## 8.2 Read Instructions

## 8.2.1 Read Data (03h)

The Read Data instruction is followed by a 3-byte address (A23 - A0), each bit being latched-in during the rising edge of SCLK. Then the memory content, at that address, is shifted out on SO, each bit being shifted out, at a Max frequency  $f_{C2}$ , during the falling edge of SCLK. The address automatically increments to the next higher address after each byte of data is shifted out allowing for a continuous stream of data. This means that the entire memory can be accessed with a single command as long as the clock continues. The command is completed by driving  $\overline{CS}$  high. The whole memory can be read with a single Read Data Bytes (READ) instruction. Any *Read Data* instruction attempting to execute while an *Erase*, *Program* or *Write* cycle is in progress, is rejected without having any effects on the cycle that is in progress.



Figure 8-6. Read Data Bytes Sequence Diagram



### 8.2.2 Fast Read (0Bh)

The Read Data at Higher Speed (Fast Read) instruction is for quickly reading data out. It is followed by a 3-byte address (A23 - A0) and a dummy byte, each bit being latched-in during the rising edge of SCLK. Then the memory content, at that address, is shifted out on SO, each bit being shifted out, at a Max frequency of  $f_{c4}$  during the falling edge of SCLK. The first byte addressed can be at any location. The address automatically increments to the next higher address after each byte of data is shifted out.



Figure 8-7. Fast Read Sequence Diagram

## 8.2.3 Dual Output Fast Read (3Bh)

The Dual Output Fast Read instruction is followed by 3-byte address (A23 - A0) and a dummy byte, each bit being latched in during the rising edge of SCLK, then the memory contents are shifted out 2-bit per clock cycle from SI and SO. The first byte addressed can be at any location. The address automatically increments to the next higher address after each byte of data is shifted out.



Figure 8-8. Dual Output Fast Read Sequence Diagram



### 8.2.4 Quad Output Fast Read (6Bh)

The Quad Output Fast Read instruction is followed by 3-byte address (A23 - A0) and a dummy byte, each bit being latched in during the rising edge of SCLK, then the memory contents are shifted out 4-bit per clock cycle from  $IO_3$ ,  $IO_2$ ,  $IO_1$  and  $IO_0$ . The first byte addressed can be at any location. The address automatically increments to the next higher address after each byte of data is shifted out.



#### Figure 8-9. Quad Output Fast Read Sequence Diagram

### 8.2.5 Dual I/O Fast Read (BBh)

The Dual I/O Fast Read instruction is similar to the Dual Output Fast Read instruction but with the capability to input the 3-byte address (A23 - 0) and a Continuous Read Mode byte 2-bits per clock by SI and SO, each bit being latched in during the rising edge of SCLK, then the memory contents are shifted out two bits per clock cycle on the SI and SO pins. The first byte addressed can be at any location. The address automatically increments to the next higher address after each byte of data is shifted out.

#### Dual I/O Fast Read with Continuous Read Mode

The Dual I/O Fast Read instruction can further reduce instruction overhead through setting the Continuous Read Mode bits (M7 - 4) after the inputs 3-byte address A23 - A0).

If the Continuous Read Mode bits (M5:M4) do not equal (1,0), the next instruction requires the first BBh instruction code, thus returning to normal operation. A Continuous Read Mode Reset instruction can be used to reset (M5:M4) before issuing normal instruction. The instruction sequence is shown in the following Figure 8-10.

If the Continuous Read Mode bits (M5:M4) = (1, 0), then the next Dual I/O fast Read instruction (after  $\overline{CS}$  is raised and then lowered) does not require the BBh instruction code. The instruction sequence is shown in the following Figure 8-11.





Figure 8-10. Dual I/O Fast Read Sequence Diagram (Initial command or previous (M5:4) ≠ (1,0))



Figure 8-11. Dual I/O Fast Read Sequence Diagram (Previous command set (M5:4) = (1,0))

## 8.2.6 Quad I/O Fast Read (EBh)

The Quad I/O Fast Read instruction is similar to the Dual I/O Fast Read instruction but with the capability to input the 3-byte address (A23-0) and a Continuous Read Mode byte and 4-dummy clocks, each bit being latched in during the rising edge of SCLK, then the memory contents are shifted out 4-bit per clock cycle from  $IO_0$ ,  $IO_1$ ,  $IO_2$ ,  $IO_3$ . The first byte addressed can be at any location. The address automatically increments to the next higher address after each byte of data is shifted out. The Quad Enable bit (QE) of Status Register must be set to enable for the Quad I/O Fast read instruction.

## Quad I/O Fast Read with Continuous Read Mode

The Quad I/O Fast Read instruction can further reduce instruction overhead through setting the Continuous Read Mode bits (M7-0) after the input Address bits (A23-0).

If the Continuous Read Mode bits M5-4 do not equal to (1,0), the next instruction requires the first EBh instruction code, thus returning to normal operation. A Continuous Read Mode Reset command can also be used to reset (M5-4) before issuing normal command. The instruction sequence is shown in the followed Figure 8-12.

If the Continuous Read Mode bits (M5-4) = (1,0), then the next Fast Read Quad I/O instruction (after  $\overline{CS}$  is raised and then lowered) does not require the EBh instruction code. The instruction sequence is shown in the followed Figure 8-13.





Figure 8-12. Quad I/O Fast Read Sequence Diagram (Initial command or previous (M5-4)  $\neq$  (1,0))



Figure 8-13. Quad I/O Fast Read Sequence Diagram (Previous command set (M5-4) = (1,0))

#### Quad I/O Fast Read with 8/16/32/64-Byte Wrap Around

The Quad I/O Fast Read instruction can also be used to access a specific portion within a page by issuing a Set Burst with Wrap (77h) instruction prior to EBh. The Set Burst with Wrap (77h) instruction can either enable or disable the Wrap Around feature for the following EBh instructions.

When Wrap Around is enabled, the data being accessed can be limited to either an 8, 16, 32 or 64-byte section of a 256-byte page. The output data starts at the initial address specified in the instruction, once it reaches the ending boundary of the 8/16/32/64-byte section, the output wraps around to the beginning boundary automatically until  $\overline{CS}$  is pulled high to terminate the instruction.

The Burst with Wrap feature allows applications that use cache to quickly fetch a critical address and then fill the cache afterwards within a fixed length (8/16/32/64-byte) of data without issuing multiple read instructions.

The Set Burst with Wrap instruction allows three Wrap Bits, W6-4 to be set. The W4 bit is used to enable or disable the Wrap Around operation while W6-5 are used to specify the length of the wrap around section within a page.



## 8.2.7 Quad I/O Word Fast Read (E7h)

The Quad I/O Word Fast Read instruction is similar to the Quad Fast Read instruction except that the lowest address bit (A0) must equal to 0 and 2 dummy clocks. The address automatically increments to the next higher address after each byte of data is shifted out. The Quad Enable bit (QE) of Status Register (S9) must be set to enable for the Quad I/O Word Fast Read instruction.

## Quad I/O Word Fast Read with Continuous Read Mode

The Quad I/O Word Fast Read instruction can further reduce instruction overhead through setting the Continuous Read Mode bits (M7-0) after the input 3-byte Address bits (A23-0).

If the Continuous Read Mode bits M5-4 do not equal to (1,0), the next instruction requires the first E7h instruction code, thus returning to normal operation. A Continuous Read Mode Reset command can also be used to reset (M5-4) before issuing normal command. The instruction sequence is shown in the followed Figure 8-14.

If the Continuous Read Mode bits (M5-4) = (1, 0), then the next Quad I/O Fast Read instruction (after  $\overline{CS}$  is raised and then lowered) does not require the E7h instruction code, the instruction sequence is shown in the followed Figure 8-15.



Figure 8-14. Quad I/O Word Fast Read Sequence Diagram (Initial command or previous (M5-4) ≠ (1,0))





## Quad I/O Word Fast Read with 8/16/32/64-Byte Wrap Around in Standard SPI Mode

The Quad I/O Fast Read instruction can also be used to access a specific portion within a page by issuing a Set Burst with Wrap (77h) instruction prior to E7h. The Set Burst with Wrap (77h) instruction can either enable or disable the Wrap Around feature for the following E7h instructions. When Wrap Around is enabled, the data being



accessed can be limited to either an 8, 16, 32 or 64-byte section of a 256-byte page. The output data starts at the initial address specified in the instruction, once it reaches the ending boundary of the 8/16/32/64-byte section, the output will wrap around to the beginning boundary automatically until  $\overline{CS}$  is pulled high to terminate the instruction.

The Burst with Wrap feature allows applications that use cache to quickly fetch a critical address and then fill the cache afterwards within a fixed length (8/16/32/64-byte) of data without issuing multiple read instructions. The Set Burst with Wrap instruction allows three Wrap Bits, W6-4 to be set. The W4 bit is used to enable or disable the Wrap Around operation while W6-5 are used to specify the length of the wrap around section within a page.

## 8.2.8 Set Burst with Wrap (77h)

The Set Burst with Wrap instruction is used in conjunction with Quad I/O Fast Read and Quad I/O Word Fast Read instruction to access a fixed length of 8/16/32/64-byte section within a 256-byte page in standard SPI mode. The Set Burst with Wrap instruction sequence is as follows:  $\overline{CS}$  goes low -> Send Set Burst with Wrap instruction -> Send 24 Dummy bits -> Send 8 Wrap bits ->  $\overline{CS}$  goes high.

If W6-4 is set by a Set Burst with Wrap instruction, all the following Fast Read Quad I/O and Word Read Quad I/O instructions will use the W6-4 setting to access the 8/16/32/64-byte section within any page. To exit the Wrap Around function and return to normal read operation, another Set Burst with Wrap instruction should be issued to set W4 = 1. The default value of W4 upon power on is 1.

	W	4 = 0	W4 = 1 (Default)		
W6, W5	Wrap Around	Wrap Length	Wrap Around	Wrap Length	
0 0	Yes	8-byte	No	N/A	
0 1	Yes	16-byte	No	N/A	
1 0	Yes	32-byte	No	N/A	
1 1	Yes	64-byte	No	N/A	

### Table 8-2. Set Burst with Wrap



Figure 8-16. Set Burst with Wrap Sequence Diagram



## 8.3 ID and Security Instructions

## 8.3.1 Read Manufacture ID/ Device ID (90h)

The Read Manufacturer/Device ID instruction is an alternative to the Release from Power-Down/Device ID instruction that provides both the JEDEC assigned Manufacturer ID and the specific Device ID.

The instruction is initiated by driving the  $\overline{CS}$  pin low and shifting the instruction code 90h followed by a 24-bit address (A23-A0) of 000000h. If the 24-bit address is initially set to 000001h, the Device ID will be read first.



Figure 8-17. Read Manufacture ID/ Device ID Sequence Diagram

## 8.3.2 Dual I/O Read Manufacture ID/ Device ID (92h)

The Dual I/O Read Manufacturer/Device ID instruction is an alternative to the Release from Power-Down/Device ID instruction that provides both the JEDEC assigned Manufacturer ID and the specific Device ID by Dual I/O.

The instruction is initiated by driving the  $\overline{CS}$  pin low and shifting the instruction code 92h followed by a 24-bit address (A23 - A0) of 000000h. If the 24-bit address is initially set to 000001h, the Device ID is read first.





Figure 8-18. Dual I/O Read Manufacture ID/ Device ID Sequence Diagram

### 8.3.3 Quad I/O Read Manufacture ID/ Device ID (94h)

The Quad I/O Read Manufacturer/Device ID instruction is an alternative to the Release from Power-Down/Device ID instruction that provides both the JEDEC assigned Manufacturer ID and the specific Device ID by quad I/O.

The instruction is initiated by driving the  $\overline{CS}$  pin low and shifting the instruction code 94h followed by a 24-bit address (A23 - A0) of 000000h and four dummy clocks. If the 24-bit address is initially set to 000001h, the Device ID is read out first.







## 8.3.4 Read JEDEC ID (9Fh)

The JEDEC ID instruction allows the 8-bit manufacturer identification to be read, followed by two bytes of device identification. The device identification indicates the memory type in the first byte, and the memory capacity of the device in the second byte. JEDEC ID instruction while an Erase or Program cycle is in progress, is not decoded, and has no effect on the cycle that is in progress. The JEDEC ID instruction should not be issued while the device is in Deep Power-Down Mode.

The device is first selected by driving  $\overline{CS}$  to low. Then, the 8-bit instruction code for the instruction is shifted in. This is followed by the 24-bit device identification, stored in the memory, being shifted out on Serial Data Output, each bit being shifted out during the falling edge of Serial Clock. The JEDEC ID instruction is terminated by driving  $\overline{CS}$  to high at any time during data output. When  $\overline{CS}$  is driven high, the device is put in the Standby Mode. Once in the Standby Mode, the device waits to be selected, so that it can receive, decode and execute instructions.





Figure 8-20. JEDEC ID Sequence Diagram

## 8.3.5 Read Unique ID Number (4Bh)

The Read Unique ID Number instruction accesses a factory-set read-only 64-bit number that is unique to each AT25QF128A device. The ID number can be used in conjunction with user software methods to help prevent copying or cloning of a system. The Read Unique ID instruction is initiated by driving the  $\overline{CS}$  pin low and shifting the instruction code 4Bh followed by a four bytes of dummy clocks. After which, the 64-bit ID is shifted out on the falling edge of SCLK as shown in Figure 8-21.



Figure 8-21. Read Unique ID Sequence Diagram



### 8.3.6 Deep Power-Down (B9h)

Although the standby current during normal operation is relatively low, standby current can be further reduced with the Deep Power-down instruction. The lower power consumption makes the Deep Power-down (DPD) instruction especially useful for battery powered applications (see ICC1 and ICC2). The instruction is initiated by driving the  $\overline{CS}$  pin low and shifting the instruction code B9h as shown in Figure 8-22.

The  $\overline{CS}$  pin must be driven high after the eighth bit has been latched. If this is not done the Deep Power down instruction is not executed. After  $\overline{CS}$  is driven high, the power-down state is entered within the time duration of  $t_{DP}$ . While in the power-down state only the Release from Deep Power-down / Device ID instruction, which restores the device to normal operation, will be recognized. All other Instructions are ignored. This includes the Read Status Register instruction, which is always available during normal operation. Ignoring all but one instruction also makes the Power Down state a useful condition for securing maximum write protection. The device always powers-up in the normal operation with the standby current of ICC1.



#### Figure 8-22. Deep Power-Down Sequence Diagram

#### 8.3.7 Release from Deep Power-Down/Read Device ID (ABh)

The Release from Power-Down or Device ID instruction is a multi-purpose instruction. It can be used to release the device from the Power-Down state or obtain the devices electronic identification (ID) number.

To release the device from the Power-Down state, the instruction is issued by driving the  $\overline{CS}$  pin low, shifting the instruction code ABh and driving  $\overline{CS}$  high Release from Power-Down will take the time duration of t<sub>RES1</sub> (See Section 9.8, AC Electrical Characteristics) before the device resumes normal operation and other instruction are accepted. The  $\overline{CS}$  pin must remain high during the t<sub>RES1</sub> time duration.

When used only to obtain the Device ID while not in the Power-Down state, the instruction is initiated by driving the  $\overline{CS}$  pin low and shifting the instruction code ABh followed by 3-dummy byte. The Device ID bits are then shifted out on the falling edge of SCLK with most significant bit (MSB) first as shown in Figure 8-23. The Device ID value for the AT25QF128A is listed in Manufacturer and Device Identification table. The Device ID can be read continuously. The instruction is completed by driving  $\overline{CS}$  high.

When used to release the device from the Power-Down state and obtain the Device ID, the instruction is the same as previously described, and shown in Figure 8-23, except that after  $\overline{CS}$  is driven high it must remain high for a time duration of t<sub>RES2</sub> (See Section 9.8, AC Electrical Characteristics). After this time duration the device resumes normal operation and other instructions are accepted. If the Release from Power-Down/Device ID instruction is issued while an Erase, Program or Write cycle is in process (when WIP equal 1) the instruction is ignored and does not effect the current cycle.





Figure 8-23. Release Power-Down Sequence Diagram



Figure 8-24. Release Power-Down/Read Device ID Sequence Diagram

## 8.3.8 Read Security Registers (48h)

The Read Security Registers instruction is similar to Fast Read instruction. The instruction is followed by a 3-byte address (A23 - A0) and a dummy byte, each bit being latched-in during the rising edge of SCLK. Then the memory content, at that address, is shifted out on SO, each bit being shifted out, at a Max frequency  $f_C$ , during the falling edge of SCLK. The first byte addressed can be at any location. The address automatically increments to the next higher address after each byte of data is shifted out. Once the A7 - A0 address reaches the last byte of the register (Byte FFh), it resets to 000h, the instruction is completed by driving  $\overline{CS}$  high.

Table 8-3.	Read Security Registers
------------	-------------------------

Address	A23-A16	A15-A12	A11-A8	A7-A0
Security Registers 1	00h	0001	0000	Byte Address
Security Registers 2	00h	0010	0000	Byte Address
Security Registers 3	00h	0011	0000	Byte Address





Figure 8-25. Read Security Registers Instruction Sequence Diagram

## 8.3.9 Erase Security Registers (44h)

The AT25QF128A provides three 256-byte Security Registers which can be erased and programmed individually. These registers may be used by the system manufacturers to store security and other important information separately from the main memory array.

The Erase Security Registers instruction is similar to Sector/Block Erase instruction. A Write Enable instruction must previously have been executed to set the Write Enable Latch bit.

The Erase Security Registers instruction sequence:  $\overline{CS}$  goes low -> sending Erase Security Registers instruction ->  $\overline{CS}$  goes high.  $\overline{CS}$  must be driven high after the eighth bit of the instruction code has been latched in otherwise the Erase Security Registers instruction is not executed. As soon as  $\overline{CS}$  is driven high, the self-timed Erase Security Registers cycle (whose duration is  $t_{SE}$ ) is initiated. While the Erase Security Registers cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Erase Security Registers cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch bit is reset. The Security Registers Lock Bit (LB) in the Status Register can be used to OTP protect the security registers. Once the LB bit is set to 1, the Security Registers are permanently locked; the Erase Security Registers instruction is ignored.

Address	A23 - A16	A15 - A12	A11 - A8	A7 - A0
Security Registers 1	00h	0001	0000	Byte Address
Security Registers 2	00h	0010	0000	Byte Address
Security Registers 3	00h	0011	0000	Byte Address

#### Table 8-4. Erase Security Registers





Figure 8-26. Erase Security Registers Instruction Sequence Diagram

## 8.3.10 Program Security Registers (42h)

The Program Security Registers instruction is similar to the Page Program instruction. It allows from 1 to 256 bytes Security Registers data to be programmed. A Write Enable instruction must previously have been executed to set the Write Enable Latch (WEL) bit before sending the Program Security Registers instruction.

The Program Security Registers instruction is entered by driving  $\overline{CS}$  low, followed by the instruction code (42h), a 3-byte address and at least one data byte on the SI pin. As soon as  $\overline{CS}$  is driven high, the self-timed Program Security Registers cycle (whose duration is  $t_{PP}$ ) is initiated. While the Program Security Registers cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Program Security Registers cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the WEL bit is reset.

If the Security Registers Lock Bit (LB3/LB2/LB1) bits are set to 1, the Security Registers are permanently locked. The Program Security Registers instruction is ignored.

Address	A23 - A16	A15 - A12	A11 - A8	A7 - A0
Security Registers 1	00h	0001	0000	Byte Address
Security Registers 2	00h	0010	0000	Byte Address
Security Registers 3	00h	0011	0000	Byte Address

## Table 8-5. Program Security Registers







### 8.3.11 Enable Reset (66h) and Reset Device (99h)

Because of the small package and the limitation on the number of pins, the AT25QF128A provides a software Reset instruction instead of a dedicated RESET pin. Once the software Reset instruction is accepted, any on-going internal operations are terminated and the device returns to its default power-on state and loses all of the current volatile settings, such as Volatile Status Register bits, Write Enable Latch (WEL) status, Program/Erase Suspend status, Continuous Read Mode bit setting (M7-M0) and Wrap Bit setting (W6-W4).

To avoid accidental reset, both Enable Reset (66h) and Reset (99h) instructions must be issued in sequence. Any other commands other than Reset (99h) after the Enable Reset (66h) command will disable the Reset Enable state. A new sequence of Enable Reset (66h) and Reset (99h) is needed to reset the device. Once the Reset command is accepted by the device, the device takes approximately 30  $\mu$ s to reset. During this period, no commands are accepted.

The Enable Reset (66h) and Reset (99h) instruction sequence is shown in Figure 8-28.

Data corruption may happen if there is an on-going or suspended internal Erase or Program operation when Reset command sequence is accepted by the device. It is recommended to check the BUSY bit and the SUS bit in Status Register before issuing the Reset command sequence.



Figure 8-28. Enable Reset (66h) and Reset (99h) Command Sequence

## 8.4 Program and Erase Instructions

## 8.4.1 Page Program (02h)

The Page Program instruction is for programming the memory. A Write Enable instruction must previously have been executed to set the Write Enable Latch bit before sending the Page Program instruction.

The Page Program instruction is entered by driving  $\overline{CS}$  Low, followed by the instruction code, 3-byte address and at least one data byte on SI. If the 8 least significant address bits (A7 - A0) are not all zero, all transmitted data that goes beyond the end of the current page are programmed from the start address of the same page (from the address whose 8 least significant bits (A7 - A0) are all zero).  $\overline{CS}$  must be driven low for the entire duration of the sequence. The Page Program instruction sequence:  $\overline{CS}$  goes low -> sending Page Program instruction -> 3-byte address on SI -> at least 1 byte of data on SI ->  $\overline{CS}$  goes high.

If more than 256 bytes are sent to the device, previously latched data are discarded and the last 256 data bytes are guaranteed to be programmed correctly within the same page. If less than 256 data bytes are sent to device, they are correctly programmed at the requested addresses without having any effects on the other bytes of the same page.  $\overline{\text{CS}}$  must be driven high after the eighth bit of the last data byte has been latched in; otherwise the Page Program instruction is not executed.

As soon as  $\overline{CS}$  is driven high, the self-timed Page Program cycle (whose duration is  $t_{PP}$ ) is initiated. While the Page Program cycle is in progress, the Status Register may be read to check the value of the Write in Progress (WIP)


bit. The Write in Progress (WIP) bit is 1 during the self-timed Page Program cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset.

A Page Program instruction applied to a page which is protected by the Block Protect (BP4, BP3, BP2, BP1, BP0) bits is not executed.



Figure 8-29. Page Program Sequence Diagram

#### 8.4.2 Quad Page Program (32h)

The Quad Page Program instruction is for programming the memory using for pins:  $IO_0$ ,  $IO_1$ ,  $IO_2$  and  $IO_3$ . To use Quad Page Program the Quad Enable (QE) bit in the Status register must be set (QE = 1). A Write Enable instruction must previously have been executed to set the Write Enable Latch bit before sending the Page Program instruction. The Quad Page Program instruction is entered by driving  $\overline{CS}$  low, followed by the command code (32h), three address bytes and at least one data byte on IO pins.

The instruction sequence is shown in Figure 8-30. If more than 256 bytes are sent to the device, previously latched data are discarded and the last 256 data bytes are guaranteed to be programmed correctly within the same page. If less than 256 data bytes are sent to device, they are correctly programmed at the requested addresses without having any effects on the other bytes of the same page.  $\overline{CS}$  must be driven high after the eighth bit of the last data byte has been latched in; otherwise the Quad Page Program instruction is not executed.

As soon as  $\overline{CS}$  is driven high, the self-timed Quad Page Program cycle (whose duration is  $t_{PP}$ ) is initiated. While the Quad Page Program cycle is in progress, the Status Register may be read to check the value of the Write in Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Quad Page Program cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch bit is reset.A Quad Page Program instruction applied to a page which is protected by the Block Protect (BP4, BP3, BP2, BP1, BP0) bits is not executed.





Figure 8-30. Quad Page Program Sequence Diagram

#### 8.4.3 Fast Page Program (F2h)

The Fast Page Program instruction is used to program the memory. A Write Enable instruction must previously have been executed to set the WEL bit before sending the Page Program instruction.

The Fast Page Program instruction is entered by driving  $\overline{CS}$  Low, followed by the instruction code, 3-byte address and at least one data byte on SI. If the 8 least significant address bits (A7-A0) are not all zero, all transmitted data that goes beyond the end of the current page are programmed from the start address of the same page (from the address whose 8 least significant bits (A7-A0) are all zero).  $\overline{CS}$  must be driven low for the entire duration of the sequence.

The Fast Page Program instruction sequence:  $\overline{CS}$  goes low -> sending Page Program instruction -> 3-byte address on SI -> at least 1 byte data on SI ->  $\overline{CS}$  goes high.

The command sequence is shown in Figure 8-31. If more than 256 bytes are sent to the device, previously latched data are discarded and the last 256 data bytes are guaranteed to be programmed correctly within the same page. If less than 256 data bytes are sent to device, they are correctly programmed at the requested addresses without having any effects on the other bytes of the same page. CS must be driven high after the eighth bit of the last data byte has been latched in; otherwise the Fast Page Program instruction is not executed.

As soon as  $\overline{CS}$  is driven high, the self-timed Page Program cycle (whose duration is  $t_{PP}$ ) is initiated. While the Page Program cycle is in progress, the Status Register may be read to check the value of the Write-in-Progress (WIP)



bit. The WIP bit is 1 during the self-timed Page Program cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the WEL bit is reset.

A Fast Page Program instruction applied to a page which is protected by the Block Protect (BP4, BP3, BP2, BP1, BP0) bits is not executed.



Figure 8-31. Fast Page Program Sequence Diagram

#### 8.4.4 Sector Erase (20h)

The Sector Erase instruction is for erasing the all data of the chosen sector. A Write Enable instruction must previously have been executed to set the Write Enable Latch bit. The Sector Erase instruction is entered by driving  $\overline{CS}$  low, followed by the instruction code, and 3-address byte on SI. Any address inside the sector is a valid address for the Sector Erase instruction.  $\overline{CS}$  must be driven low for the entire duration of the sequence.

The Sector Erase instruction sequence:  $\overline{CS}$  goes low -> sending Sector Erase instruction -> 3-byte address on SI ->  $\overline{CS}$  goes high.  $\overline{CS}$  must be driven high after the eighth bit of the last address byte has been latched in; otherwise the Sector Erase instruction is not executed. As soon as  $\overline{CS}$  is driven high, the self-timed Sector Erase cycle (whose duration is  $t_{SE}$ ) is initiated. While the Sector Erase cycle is in progress, the Status Register may be read to check the value of the Write-in-Progress (WIP) bit. The WIP bit is 1 during the self-timed Sector Erase cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset. A Sector Erase instruction applied to a sector which is protected by the Block Protect (BP4, BP3, BP2, BP1, BP0) bits is not executed.



Figure 8-32. Sector Erase Sequence Diagram

#### 8.4.5 32KB Block Erase (52h)

The 32 KB Block Erase instruction is for erasing all data of a chosen block. A Write Enable instruction must have been previously executed to set the WEL bit. The 32 kB Block Erase instruction is entered by driving  $\overline{CS}$  low, followed by the instruction code, and 3-byte address on SI. Any address inside the block is a valid address for the 32 KB Block Erase instruction.  $\overline{CS}$  must be driven low for the entire duration of the sequence.



The 32 KB Block Erase instruction sequence:  $\overline{CS}$  goes low -> sending 32 kB Block Erase instruction -> 3-byte address on SI ->  $\overline{CS}$  goes high.  $\overline{CS}$  must be driven high after the eighth bit of the last address byte has been latched in; otherwise the 32 kB Block Erase instruction is not executed.

As soon as  $\overline{CS}$  is driven high, the self-timed Block Erase cycle (whose duration is  $t_{BE}$ ) is initiated. While the Block Erase cycle is in progress, the Status Register may be read to check the value of the Write-in-Progress (WIP) bit. The WIP bit is 1 during the self-timed Block Erase cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset. A 32 kB Block Erase instruction applied to a block which is protected by the Block Protect (BP4, BP3, BP2, BP1, BP0) bits is not executed.



Figure 8-33. 32KB Block Erase Sequence Diagram

#### 8.4.6 64KB Block Erase (D8h)

The 64 KB Block Erase instruction is for erasing the all data of the chosen block. A Write Enable instruction must previously have been executed to set the WEL bit. The 64 KB Block Erase instruction is entered by driving  $\overline{CS}$  low, followed by the instruction code, and 3-byte address on SI. Any address inside the block is a valid address for the 64 KB Block Erase instruction.  $\overline{CS}$  must be driven low for the entire duration of the sequence.

The 64 KB Block Erase instruction sequence:  $\overline{CS}$  goes low sending 64 KB Block Erase instruction 3-byte address on SI  $\overline{CS}$  goes high.  $\overline{CS}$  must be driven high after the eighth bit of the last address byte has been latched in; otherwise the 64 KB Block Erase instruction is not executed. As soon as  $\overline{CS}$  is driven high, the self-timed Block Erase cycle (whose duration is t<sub>BE</sub>) is initiated.

While the Block Erase cycle is in progress, the Status Register may be read to check the value of the Write-in-Progress (WIP) bit. The WIP bit is 1 during the self-timed Block Erase cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the WEL bit is reset. A 64 KB Block Erase instruction applied to a block which is protected by the Block Protect (BP4, BP3, BP2, BP1, BP0) bits is not executed.



Figure 8-34. 64KB Block Erase Sequence Diagram



#### 8.4.7 Chip Erase (60/C7h)

The Chip Erase instruction sets all memory within the device to the erased state of all 1s (FFh). A Write Enable instruction must be executed before the device accepts the Chip Erase Instruction (Status Register bit WEL must equal 1). The instruction is initiated by driving the  $\overline{CS}$  pin low and shifting the instruction code C7h or 60h. The Chip Erase instruction sequence is shown in Figure 8-35.

The  $\overline{CS}$  pin must be driven high after the eighth bit has been latched. If this is not done the Chip Erase instruction is not executed. After  $\overline{CS}$  is driven high, the self-timed Chip Erase instruction commences for a time duration of  $t_{CE}$ . While the Chip Erase cycle is in progress, the Read Status Register instruction may still be accessed to check the status of the WIP bit.

The WIP bit is a 1 during the Chip Erase cycle and becomes a 0 when finished and the device is ready to accept other Instructions again. After the Chip Erase cycle has finished the WEL bit in the Status Register is cleared to 0. The Chip Erase instruction is executed only if all Block Protect (BP2, BP1, and BP0) bits are 0. The Chip Erase instruction is ignored if one or more sectors are protected.



#### Figure 8-35. Chip Erase Sequence Diagram

#### 8.4.8 Erase / Program Suspend (75h)

The Erase/Program Suspend instruction allows the system to interrupt a Sector or Block Erase operation, then read from or program data to any other sector. The Erase/Program Suspend instruction also allows the system to interrupt a Page Program operation and then read from any other page or erase any other sector or block. The Erase/Program Suspend instruction sequence is shown in Figure 8-36.

The Write Status Registers instruction (01h) and Erase instructions (20h, D8h, C7h, 60h, 44h) are not allowed during Erase Suspend. Erase Suspend is valid only during the Sector or Block erase operation. If written during the Chip Erase operation, the Erase Suspend instruction is ignored. The Write Status Registers instruction (01h), and Program instructions (02h, 42h) are not allowed during Program Suspend. Program Suspend is valid only during the Page Program operation.



Figure 8-36. Erase/Program Suspend Command Sequence



#### 8.4.9 Erase / Program Resume (7Ah)

The Erase/Program Resume instruction 7Ah must be written to resume the Sector or Block Erase operation or the Page Program operation after an Erase/Program Suspend. The Resume instruction 7Ah is accepted by the device only if the SUS bit in the Status Register equals to 1 and the WIP bit equals to 0.

After the Resume instruction is issued the SUS bit is cleared from 1 to 0 immediately, the WIP bit is set from 0 to 1 within 200 ns and the Sector or Block completes the erase operation or the page completes the program operation. If the SUS bit equals to 0 or the WIP bit equals to 1, the Resume instruction 7Ah is ignored by the device. The Erase/Program Resume instruction sequence is shown in Figure 8-37.



Figure 8-37. Erase/Program Resume Command Sequence

#### 8.4.10 Read Serial Flash Discoverable Parameter (5Ah)

The Serial Flash Discoverable Parameter (SFDP) standard provides a consistent method of describing the functional and feature capabilities of serial Flash devices in a standard set of internal parameter tables. These parameter tables can be interrogated by host system software to enable adjustments needed to accommodate divergent features from multiple vendors. The concept is similar to the one found in the Introduction of JEDEC Standard, JESD68 on CFI. SFDP is a standard of JEDEC Standard No. 216.



Figure 8-38. Read Serial Flash Discoverable Parameter Command Sequence Diagram



#### Table 8-6. SFDP Signature and Headers

Description	Comment	Address Byte	Bits	Data (binary)	Data (hex)
SFDP Signature		00h	07:00	0101 0011	53h
		01h	15:08	0100 0110	46h
		02h	23:16	0100 0100	44h
		03h	31:24	0101 0110	50h
SFDP Minor Revision	Start from 00h	04h	07:00	0000 0000	00h
SFDP Major Revision	Start from 01h	05h	15:08	0000 0001	01h
Number of Parameters Headers	Start from 00h	06h	23:16	0000 0001	01h
Reserved	FFh	07h	31:24	1111 1111	FFh
JEDEC Parameter ID (LSB)	JEDEC Parameter ID (LSB) = 00h	08h	07:00	0000 0000	00h
Parameter Table Minor Revision	Start from 00h	09h	15:08	0000 0000	00h
Parameter Table Major Revision	Start from 01h	0Ah	23:16	0000 0001	01h
Parameter Table Length (double words)	How many DWORDs in the parameter table	0Bh	31:24	0000 1001	09h
Parameter Table Pointer	Address of Adesto	0Ch	07:00	0011 0000	30h
	Parameter Table	0Dh	15:08	0000 0000	00h
		0Eh	23:16	0000 0000	00h
Reserved	FFh	0Fh	31:24	1111 1111	FFh
ID Number LSB (Manufacturer ID)	Adesto Manufacturer ID	10h	07:00	0001 1111	1Fh
Parameter Table Minor Revision	Start from 00h	11h	15:08	0000 0000	00h
Parameter Table Major Revision	Start from 01h	12h	23:16	0000 0001	01h
Parameter Table Length (double words)	How many DWORDs in the parameter table	13h	31:24	0000 0011	03h
Parameter Table	Address of Adesto	14h	07:00	0110 0000	60h
Pointer (PTP)	Parameter Table	15h	15:08	0000 0000	00h
		16h	23:16	0000 0000	00h
Reserved	FFh	17h	31:24	1111 1111	FFh



#### Table 8-7. SFDP Parameters Table 1

Description	Comment	Address Byte	Bits	Data (binary)	Data (hex)
Erase Granularity	01: 4KB available 11: 4KB not available	30h	01:00	01	E5h
Write Granularity	0: 1 byte 1: 64 bytes or larger		02	1	
Volatile Status Register Block Protect Bits	0: Nonvolatile status bit 1: Volatile status bit	-	03	0	
Volatile Status Register Write Enable Opcode	0: 50h Opcode 1: 60h Opcode (If target Flash Status register is non- volatile, then bits 3 and 4 must be set to 2'b00.		04	0	
Reserved			07:05	111	
4KB Erase Opccde	Opcode or FFh	31h	15:08	0010 0000	20h
Fast Dual Read Output (1 -1 -2)	0: Not supported, 1: Supported	32h	16	1	F1h
Number of Address Bytes	00: 3 Byte only 01: 3 or 4 Byte 10: 4 Byte only 11: Reserved		18:17	00	
Double Transfer Rate (DTR) Clocking	0: Not supported, 1: Supported	-	19	0	
Fast Dual I/O Read (1-2- 2)	0: Not supported, 1: Supported		20	1	
Fast Quad I/O Read (1-4-4)	0: Not supported, 1: Supported	-	21	1	-
Fast Quad Output Read (1-1-4)	0: Not supported, 1: Supported		22	1	
Reserved	FFh		23	1	
Reserved	FFh	33h	31:24	1111 1111	FFh
Flash Memory Density		37h:34h	31:0	0000 0111 1111 1111 1111 1111 1111 1111 1111 1111	07FFFFFFh
Fast Quad I/O (1-4-4) Number of dummy clocks	Number of dummy clocks	38h	04:00	00100	44h
Fast Quad I/O (1-4-4) Number of mode bits	Number of mode bits		07:05	010	
Fast Quad I/O (1-4-4) Read Opcode	Opcode or FFh	39h	15:08	1110 1011	EBh



#### Table 8-7. SFDP Parameters Table 1 (continued)

Description	Comment	Address Byte	Bits	Data (binary)	Data (hex)
Fast Quad Output (1-1-4) Number of dummy clocks	Number of dummy clocks	3Ah	20:16	01000	08h
Fast Quad Output (1-1-4) Number of mode bits	Number of mode bits		23:21	000	
Fast Quad Output (1-1-4) Read Opcode	Opcode or FFh	3Bh	31:24	0110 1011	6Bh
Fast Dual Output (1-1-2) Number of dummy clocks	Number of dummy clocks	3Ch	04:00	01000	08h
Fast Dual Output (1-1-2) Number of mode bits	Number of mode bits		07:05	000	•
Fast Dual Output (1-1-2) Read Opcode	Opcode or FFh	3Dh	15:08	0011 1011	3Bh
Fast Dual I/O (1-2-2) Number of dummy clocks	Number of dummy clocks	3Eh	20:16	00010	42h
Fast Dual I/O (1-2-2) Number of mode bits	Number of mode bits		23:21	010	
Fast Dual I/O (1-2-2) Read Opcode	Opcode or FFh	3Fh	31:24	1011 1011	BBh
Fast Dual (2-2-2)	0: Not supported, 1: Supported			0	EEh
Reserved	FFh		03:01	111	
Fast Quad (4-4-4)	0: Not supported, 1: Supported		04	0	
Reserved	FFh		07:05	111	
Reserved	FFh	41h	15:08	1111 1111	FFh
Reserved	FFh	42h	23:16	1111 1111	FFh
Reserved	FFh	43h	31:24	1111 1111	FFh
Reserved	FFh	44h	07:00	1111 1111	FFh
Reserved	FFh	45h	15:08	1111 1111	FFh
Fast Dual (2-2-2) Number of dummy clocks	Number of dummy clocks	46h	20:16	0 0000	00h
Fast Dual (2-2-2) Number of mode bits	Number of mode bits		23:21	000	
Fast Dual (2-2-2) Read Opcode	Opcode or FFh	47h	31:24	0000 0000	00h
Reserved	FFh	48h	07:00	1111 1111	FFh
Reserved	FFh	49h	15:08	1111 1111	FFh



#### Table 8-7. SFDP Parameters Table 1 (continued)

Description	Comment	Address Byte	Bits	Data (binary)	Data (hex)
Fast Quad QPI (4-4-4) Number of dummy clocks	Number of dummy clocks	4Ah	20:16	00000	00h
Fast Quad QPI (4-4-4) Number of mode bits	Number of mode bits	_	23:21	000	
Fast Quad QPI (4-4-4) Read Opcode	Opcode or FFh	4Bh	31:24	0000 0000	00h
Erase type-1 Size	4KB = 2^0Ch, 32KB = 2^0Fh, 64KB = 2^10h; (2^Nbyte)	4Ch	07:00	0000 1100	0Ch
Erase type-1 Opcode	Opcode or FFh	4Dh	15:08	0010 0000	20h
Erase type-2 Size	4KB = 2^0Ch, 32KB = 2^0Fh, 64KB = 2^10h; (2^Nbyte)	4Eh	23:16	0000 1111	0Fh
Erase type-2 Opcode	Opcode or FFh	4Fh	31:24	0101 0010	52h
Erase Type-3 Size	4KB = 2^0Ch, 32KB = 2^0Fh, 64KB = 2^10h; (2^Nbyte)	50h	07:00	0001 0000	10h
Erase Type-3 Opcode	Opcode or FFh	51h	15:08	1101 1000	D8h
Erase Type-4 Size	4KB = 2^0Ch, 32KB = 2^0Fh, 64KB = 2^10h; (2^Nbyte)	52h	23:16	0000 0000	00h
Erase Type-4 Opcode	Opcode or FFh	53h	31:24	1111 1111	FFh
Vcc Maximum Voltage	2000h: 2.0V	60h	7:0	0000 0000	00h
	2700h: 2.7V 3600h: 3.6V		15:8	0011 0110	36h
Vcc Minimum Voltage	1650h: 1.65V	62h	7:0	0000 0000	00h
	2250h: 2.25V 2350h: 2.35V 2700h: 2.70V	63h	15:8	0010 0112	27h



#### Table 8-7. SFDP Parameters Table 1 (continued)

Description	Comment	Address Byte	Bits	Data (binary)	Data (hex)
Hardware RESET Pin	0: Not supported 1: Supported	65h:64h	0	0	F99Eh
Hardware HOLD Pin	0: Not supported 1: Supported		1	1	
Deep Power Down Mode	0: Not supported 1: Supported		2	1	
Software Reset	0: Not supported 1: Supported		3	1	
Software Reset Opcode	Issue Reset Enable (66h) before Reset (99h)	-	11:4	99h	
Program Suspend/Resume	0: Not supported 1: Supported		12	1	
Erase Suspend/Resume	0: Not supported 1: Supported	-	13	1	
Reserved		-	14	1	
Wrap-around Read Mode	0: Not supported 1: Supported	-	15	1	
Wrap-around Read Mode Opcode		66h	23:16	0111 0111	77h
Wrap-around Read Data Length	08h: Supports 8b wrap-around 16h: Supports 8b and 16b 32h: Supports 8b, 16, and 32b 64h: Supports 8b, 16b, 32b, and 64b	67h	31:24	0110 0100	64h
Individual Block Lock	0: Not supported 1: Supported	69h:68h	0	0	C000h
Individual Block Lock (Volatile/Non-volatile)	0: Not supported 1: Supported	-	1	0	•
Individual Block Lock Opcode			9:2	0000 0000	
Individual Block Lock (Volatile protect bit, default protect status)	0: Not supported 1: Supported		10	0	
Secured OTP	0: Not supported 1: Supported		11	0	
Read Lock	0: Not supported 1: Supported		12	0	
Permanent Lock	0: Not supported 1: Supported		13	0	
Reserved			15:14	11	
Reserved		6Bh:6Ah	31:16	1111 1111 1111 1111	FFFFh



# 9. Electrical Characteristics

## 9.1 Absolute Maximum Ratings

#### Table 9-1. Absolute Maximum Ratings

Parameter	Symbol	Conditions	Range	Units
Supply Voltage	VCC		-0.5 to 4	V
Voltage Applied to Any Pin	VIO	Relative to Ground	-0.5 to 4	V
Transient Voltage on any Pin	VIOT	<20nS Transient Relative to Ground	-2.0 to VCC + 2.0	V
Storage Temperature	TSTG		-65 to +150	°C
Electrostatic Discharge Voltage	VESD	Human Body Model <sup>(1)</sup>	-2000 to +2000	V

Notes:

1. JEDEC Std JESD22-A114 (C1 = 100 pF, R1 = 1500Ω, R2 = 500Ω)

## 9.2 Operating Ranges

#### Table 9-2. Operating Range

Parameter	Symbol	Conditions	Min	Мах	Unit
Supply Voltage	VCC		2.7	3.6	V
	ТА	Industrial	-40	+85	°C
Operating Temperature	IA	Extended	-40	+105	°C

### 9.3 Data Retention and Endurance

#### Table 9-3. Data Retention and Endurance

Parameter	Condition	Max Temperature	Min	Мах	Units
Eraso/Program Cyclos	4 KB sector, 32/64 KB block, or full chip	85 °C	100,000		Cycles
Erase/Program Cycles		105 °C	10,000		Cycles
Data Retention Full temperature range	85 °C	20		Years	
	range	105 °C	10		Years



## 9.4 Latch Up Characteristics

#### Table 9-4. Latch-up Characteristics

Parameter	Min	Мах
Input Voltage Respect To GND on I/O Pins	-1.0V	VCC + 1.0V
VCC Current	-100 mA	100 mA

## 9.5 Power-up Timing

#### Table 9-5. Power-up Timing

Symbol	Parameter	Min	Мах	Unit
t <sub>VSL</sub>	VCC (min) To $\overline{CS}$ low	300		US



Figure 9-1. Power-up Timing and Voltage Levels



## 9.6 DC Electrical Characteristics

Table 9-6 shows the DC electrical characteristics at 85 °C,

Table 9-6.	DC Electrical	Characteristics — 85 °C
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Symbol	Parameter	Test Condition	Min	Тур	Мах	Units
Ι <sub>U</sub>	Input Leakage Current				±2	μA
I <sub>LO</sub>	Output Leakage Current				±2	μA
ICC <sub>1</sub>	Standby Current	$\overline{\text{CS}}$ = VCC, VIN = VCC or GND		13	25	μA
ICC <sub>2</sub>	Deep Power-Down Current	$\overline{\text{CS}}$ = VCC, VIN = VCC or GND		2	5	μA
ICC <sub>3</sub>	Operating Current:	SCLK = 0.1VCC/0.9VCC, at 120 MHz, Q = Open (*1,*,2*4 I/O)		12	18	mA
1003	(Read)	SCLK = 0.1VCC/0.9VCC, at 80MHz,Q = Open (*1,*,2*4 I/O)		10	16	mA
ICC <sub>4</sub>	Operating Current (Page Program)	CS = VCC		15	20	mA
ICC <sub>5</sub>	Operating Current (WRSR)	$\overline{\text{CS}}$ = VCC			5	mA
ICC <sub>6</sub>	Operating Current (Sector Erase)	CS = VCC		9	15	mA
ICC <sub>7</sub>	Operating Current (Block Erase)	CS = VCC		9	15	mA
ICC <sub>8</sub>	Operating Current (Chip Erase)	CS = VCC		9	15	mA
V <sub>IL</sub>	Input Low Voltage		-0.5		0.2VCC	V
V <sub>IH</sub>	Input High Voltage		0.8 VCC		VCC+0.4	V
V <sub>OL</sub>	Output Low Voltage	IOL = 100 μA			0.4	V
V <sub>OH</sub>	Output High Voltage	IOH = -100 μA	VCC-0.2			V



Table 9-7 shows the DC electrical characteristics at 105 °C.

Table 9-7. DC Electrical Characteristics — 105 °C

Symbol	Parameter	Test Condition	Min	Тур	Мах	Units
ILI	Input Leakage Current				±2	μA
I <sub>LO</sub>	Output Leakage Current				±2	μA
ICC <sub>1</sub>	Standby Current	$\overline{\text{CS}}$ = VCC, VIN = VCC or GND		20	30	μA
ICC <sub>2</sub>	Deep Power-Down Current	$\overline{\text{CS}}$ = VCC, VIN = VCC or GND		5	8	μΑ
ICC <sub>3</sub>	Operating Current:	SCLK = 0.1VCC/0.9VCC, at 120 MHz,Q = Open (*1,*,2*4 I/O)		12	18	mA
1003	(Read)	SCLK = 0.1VCC/0.9VCC, at 80MHz,Q = Open(*1,*,2*4 I/O)		10	16	mA
ICC <sub>4</sub>	Operating Current (Page Program)	CS = VCC		15	20	mA
ICC <sub>5</sub>	Operating Current (WRSR)	$\overline{\text{CS}}$ = VCC			5	mA
ICC <sub>6</sub>	Operating Current (Sector Erase)	CS = VCC		9	15	mA
ICC <sub>7</sub>	Operating Current (Block Erase)	CS = VCC		9	15	mA
ICC <sub>8</sub>	Operating Current (Chip Erase)	CS = VCC		9	15	mA
V <sub>IL</sub>	Input Low Voltage		-0.5		0.2VCC	V
V <sub>IH</sub>	Input High Voltage		0.8VCC		VCC+0.4	V
V <sub>OL</sub>	Output Low Voltage	IOL = 100 μA			0.4	V
V <sub>OH</sub>	Output High Voltage	IOH = -100 μA	VCC-0.2			V



## 9.7 AC Measurement Conditions

Symbol	Parameter	Min	Тур	Max	Unit	Conditions
CL	Load Capacitance			30	pF	
t <sub>R</sub> , t <sub>F</sub>	Input Rise and Fall time			5	ns	
V <sub>IN</sub>	Input Pause Voltage	0.2	/CC to 0.8\	/CC	V	
IN	Input Timing Reference Voltage	0.5VCC		V		
OUT	Output Timing Reference Voltage	0.5VCC		V		

#### Table 9-8. AC Measurement Conditions



#### Figure 9-2. AC Measurement I/O Waveform

### 9.8 AC Electrical Characteristics

Table 9-9 shows the AC electrical characteristics at 85 °C. .

Symbol	Parameter	Min	Тур	Max	Units
Fc <sub>1</sub>	Clock frequency for Quad Output Fast Read (6Bh) on 3.0V - 3.6V power supply.	DC		133	MHz
Fc <sub>2</sub>	Clock frequency for Read Data (03h) on 2.7V - 3.6V power supply.	DC		70	MHz
Fc <sub>3</sub>	Clock frequency except for Quad Output Fast Read (6Bh) or Read Data (03h) on 3.0V - 3.6V power supply.	DC		120	MHz
Fc <sub>4</sub>	Clock frequency except for Read Data (03h) on 2.7V - 3.6V power supply.	DC		108	MHz
t <sub>CLH</sub>	Serial Clock High Time	3.75			ns
t <sub>CLL</sub>	Serial Clock Low Time	3.75			ns
t <sub>CLCH</sub>	Serial Clock Rise Time (Slew Rate)	0.1 <sup>(1)</sup>			V/ns
t <sub>CHCL</sub>	Serial Clock Fall Time (Slew Rate)	0.1 <sup>(1)</sup>			V/ns
t <sub>SLCH</sub>	CS Active Setup Time	5			ns
t <sub>CHSH</sub>	CS Active Hold Time	5			ns
t <sub>shCH</sub>	CS Not Active Setup Time	5			ns
t <sub>CHSL</sub>	CS Not Active Hold Time	5			ns



Symbol	Parameter	Min	Тур	Max	Units
t <sub>SHSL</sub>	CS High Time (read/write)	20			ns
t <sub>shqz</sub>	Output Disable Time			6	ns
t <sub>CLQX</sub>	Output Hold Time	0			ns
t <sub>DVCH</sub>	Data In Setup Time	2			ns
t <sub>CHDX</sub>	Data In Hold Time	2			ns
t <sub>HLCH</sub>	HOLD Low Setup Time (relative to Clock)	5			ns
t <sub>HHCH</sub>	HOLD High Setup Time (relative to Clock)	5			ns
t <sub>CHHL</sub>	HOLD High Hold Time (relative to Clock)	5			ns
t <sub>CHHH</sub>	HOLD Low Hold Time (relative to Clock)	5			ns
t <sub>HLQZ</sub>	HOLD Low To High-Z Output			6	ns
t <sub>HHQX</sub>	HOLD Low To Low-Z Output			6	ns
t <sub>CLQV</sub>	Clock Low To Output Valid			7	ns
t <sub>WHSL</sub>	Write Protect Setup Time Before $\overline{CS}$ Low	20			ns
t <sub>SHWL</sub>	Write Protect Hold Time After $\overline{CS}$ High	100			ns
t <sub>DP</sub>	CS High To Deep Power-Down Mode			20	μs
t <sub>RES1</sub>	CS High To Standby Mode Without Electronic Signature Read			20	μs
t <sub>RES2</sub>	CS High To Standby Mode With Electronic Signature Read			20	μs
t <sub>sus</sub>	CS High To Next Instruction After Suspend			20	μs
t <sub>RST_R</sub>	CS High To Next Instruction After Reset (from read)			20	
t <sub>RST_P</sub>	CS High To Next Instruction After Reset (from program)			20	
t <sub>RST_E</sub>	CS High To Next Instruction After Reset (from erase)			12	
t <sub>w</sub>	Write Status Register Cycle Time		5	30 <sup>(2)</sup>	ms
t <sub>BP1</sub>	Byte Program Time (First Byte)		30	50	μs
t <sub>BP2</sub>	Additional Byte Program Time (After First Byte)		2.5	12	μs
t <sub>PP</sub>	Page Programming Time		0.6	2.4	ms
t <sub>SE</sub>	Sector Erase Time		70	300	ms
t <sub>BE</sub>	Block Erase Time (32K Bytes/64K Bytes)		0.15/ 0.25	1.6/2.0	sec
t <sub>CE</sub>	Chip Erase Time		30	120	sec

### Table 9-9. AC Electrical Characteristics — 85 °C (continued)

#### Notes:

1. Tested with clock frequency lower than 50 MHz.

2. For multiple bytes after first byte within a page,  $t_{BPn} = t_{BP1} + t_{BP2} * N$ , where N is the number of bytes programmed.



Table 9-10 shows the AC electrical characteristics at 105 °C.

Table 9-10. AC Electrical Characteristics - 105 °C

Symbol	Parameter	Min	Тур	Max	Units
Fc <sub>1</sub>	Clock frequency for Quad Output Fast Read (6Bh) on 3.0V - 3.6V power supply.	DC		120	MHz
Fc <sub>2</sub>	Clock frequency for Read Data (03h) on 2.7V - 3.6V power supply.	DC		70	MHz
Fc <sub>3</sub>	Clock frequency except for Quad Output Fast Read (6Bh) or Read Data (03h) on 3.0V - 3.6V power supply.	DC		120	Mhz
Fc <sub>4</sub>	Clock frequency except for Read Data (03h) on 2.7V - 3.6V power supply.	DC		108	MHz
t <sub>CLH</sub>	Serial Clock High Time	4			ns
t <sub>CLL</sub>	Serial Clock Low Time	4			ns
t <sub>CLCH</sub>	Serial Clock Rise Time (Slew Rate)	0.1 <sup>(1)</sup>			V/ns
t <sub>CHCL</sub>	Serial Clock Fall Time (Slew Rate)	0.1 <sup>(1)</sup>			V/ns
t <sub>sLCH</sub>	CS Active Setup Time	5			ns
t <sub>CHSH</sub>	CS Active Hold Time	5			ns
t <sub>shCh</sub>	CS Not Active Setup Time	5			ns
t <sub>CHSL</sub>	CS Not Active Hold Time	5			ns
t <sub>SHSL</sub>	CS High Time (read/write)	20			ns
t <sub>sHQZ</sub>	Output Disable Time			6	ns
t <sub>CLQX</sub>	Output Hold Time	0			ns
t <sub>DVCH</sub>	Data In Setup Time	2			ns
t <sub>CHDX</sub>	Data In Hold Time	2			ns
t <sub>HLCH</sub>	HOLD Low Setup Time (relative to Clock)	5			ns
t <sub>HHCH</sub>	HOLD High Setup Time (relative to Clock)	5			ns
t <sub>CHHL</sub>	HOLD High Hold Time (relative to Clock)	5			ns
t <sub>CHHH</sub>	HOLD Low Hold Time (relative to Clock)	5			ns
t <sub>HLQZ</sub>	HOLD Low To High-Z Output			6	ns
t <sub>HHQX</sub>	HOLD Low To Low-Z Output			6	ns
t <sub>CLQV</sub>	Clock Low To Output Valid			7	ns
t <sub>WHSL</sub>	Write Protect Setup Time Before $\overline{CS}$ Low	20			ns
t <sub>SHWL</sub>	Write Protect Hold Time After $\overline{CS}$ High	100			ns
t <sub>DP</sub>	CS High To Deep Power-Down Mode			20	μs
t <sub>RES1</sub>	CS High To Standby Mode Without Electronic Signature Read			20	μs
t <sub>RES2</sub>	CS High To Standby Mode With Electronic Signature Read			20	μs
t <sub>sus</sub>	CS High To Next Instruction After Suspend			20	μs



Symbol	Parameter	Min	Тур	Мах	Units
t <sub>RST_R</sub>	CS High To Next Instruction After Reset (from read)			20	
t <sub>RST_P</sub>	CS High To Next Instruction After Reset (from program)		20		
t <sub>RST_E</sub>	CS High To Next Instruction After Reset (from erase)			12	
t <sub>w</sub>	Write Status Register Cycle Time		5	30 <sup>(2)</sup>	ms
t <sub>BP1</sub>	Byte Program Time (First Byte)		30	50	μs
t <sub>BP2</sub>	Additional Byte Program Time (After First Byte)		2.5	12	μs
t <sub>PP</sub>	Page Programming Time		0.6	2.4	ms
t <sub>SE</sub>	Sector Erase Time		70	300	ms
t <sub>BE</sub>	Block Erase Time (32K Bytes/64K Bytes)		0.15/ 0.25	1.6/2.0	sec
t <sub>CE</sub>	Chip Erase Time		30	120	sec









Figure 9-4. Output Timing





Figure 9-5. HOLD Timing



Figure 9-6. WP Timing



# 10. Ordering Information



Ordering Code	Package Type	Lead Finish	Operating Voltage	Maximum Frequency	Operating Range
AT25QF128A-SHB-T	8S4		2.7 - 3.6V	133 MHz <sup>(1)</sup>	-40 °C to 85 °C
AT25QF128A-MHB-T <sup>(2)</sup>	8MA1	NiPdAu	2.7 - 3.00		-40 0 10 85 0
AT25QF128A-SHBHD-T	8S4	-	2.7 - 3.6V	120 MHz	-40 °C to 105 °C

1. Only for Quad Output Fast Read (6Bh) command with 3.0V - 3.6V power supply.

2. Contact Adesto for more information.

	Package Type
8S4	8-lead, 0.208" Wide, Plastic Gull Wing Small Outline Package (EIAJ SOIC)
8MA1	8-pad (5 x 6 x 0.6 mm body), Thermally Enhanced Plastic Ultra-Thin Dual Flat No-lead (UDFN)



## 11. Package Information

### 11.1 Package 8-Pin SOP 208-mil









# 12. Revision History

Table 12-1. Document Revision History	Table 12-1.	Document Revision History
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Revision	Date	Change Description
А	03/2019	Initial release.





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